



## N-Channel Enhancement Mode Field Effect Transistor

### Product Summary

- $V_{DS}$  40V
- $I_D$  50A
- $R_{DS(ON)}$ ( at  $V_{GS}=10V$ ) 4.5m $\Omega$
- $R_{DS(ON)}$ ( at  $V_{GS}=4.5V$ ) 6m $\Omega$
- 100% EAS Tested

### General Description

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$

### Applications

- High current load applications
- Load switching
- Hard switched and high frequency circuits
-



# YJQ50N04B

## ■ Electrical Characteristics (T<sub>J</sub>=25 unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =250μA	40	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V	-	-	1	μA
		V <sub>DS</sub> =40V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	-	-	100	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V, V <sub>DS</sub> =0V	-	-	±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.5	2.5	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =25A	-	3.3	4.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	-	4.5	6	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =25A, V <sub>GS</sub> =0V	-	0.8	1.2	V
Gate resistance	R <sub>G</sub>	f=1MHz, Open drain	-	3.5	-	Ω
Maximum Body-Diode Continuous Current	I <sub>S</sub>		-	-	50	A
<b>Dynamic Parameters</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, f=1MHz	-	4150	-	pF
Output Capacitance	C <sub>oss</sub>		-	430	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	420	-	
<b>Switching Parameters</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =25A	-	92	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	9	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	27	-	
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =25A, di/dt=100A/us	-	65	-	nC
Reverse Recovery Time	t <sub>rr</sub>		-	53	-	ns
Turn-on Delay Time	t <sub>D(on)</sub>	V <sub>GS</sub> =10V, V <sub>DD</sub> =20V, I <sub>D</sub> =25A R <sub>GEN</sub> =2.2Ω	-	14	-	ns
Turn-on Rise Time	t <sub>r</sub>		-	119	-	
Turn-off Delay Time	t <sub>D(off)</sub>		-	61	-	
Turn-off fall Time	t <sub>f</sub>		-	11	-	

A. Repetitive rating; pulse width limited by max. junction temperature.

B. T<sub>J</sub>=25°C, V<sub>DD</sub>=30V, V<sub>G</sub>=10V, R<sub>G</sub>=25Ω, L=2mH, I<sub>AS</sub>=20A.

C. P<sub>q</sub> is based on max. junction temperature, using junction-case thermal resistance.

D. The value of R<sub>θJA</sub> is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in the still air environment with T<sub>A</sub> =25°C. The maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.



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## Typical Electrical and Thermal Characteristics Diagrams

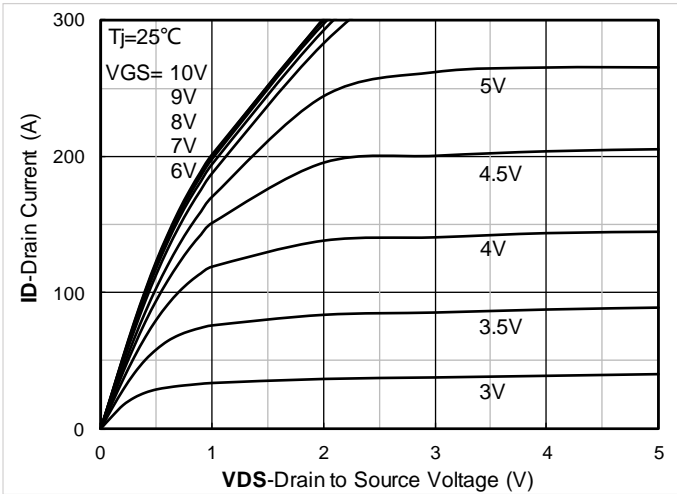


Figure 1. Output Characteristics

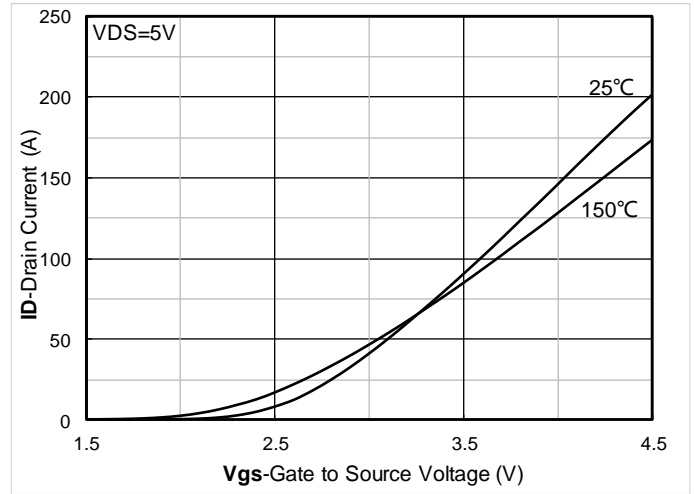


Figure 2. Transfer Characteristics

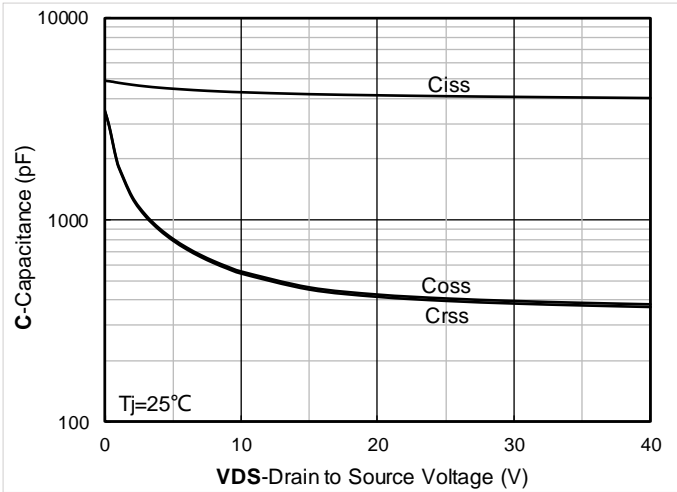


Figure 3. Capacitance Characteristics

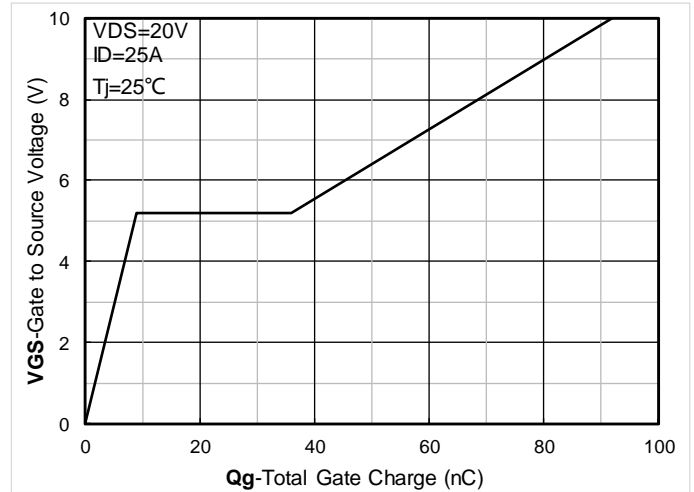


Figure 4. Gate Charge

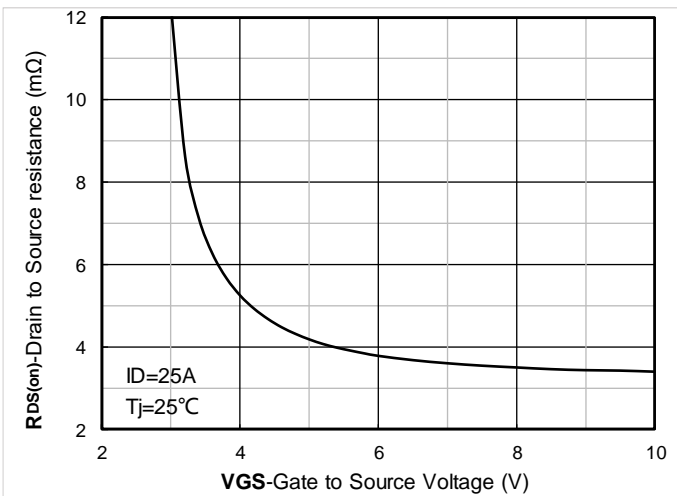


Figure 5. On-Resistance vs Gate to Source Voltage

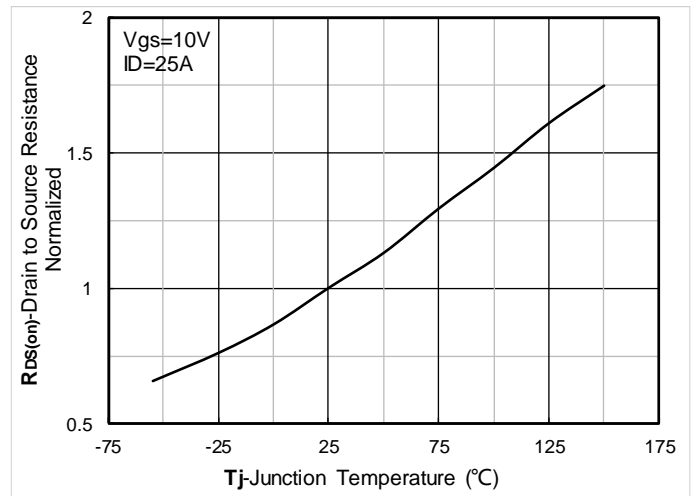


Figure 6. Normalized On-Resistance



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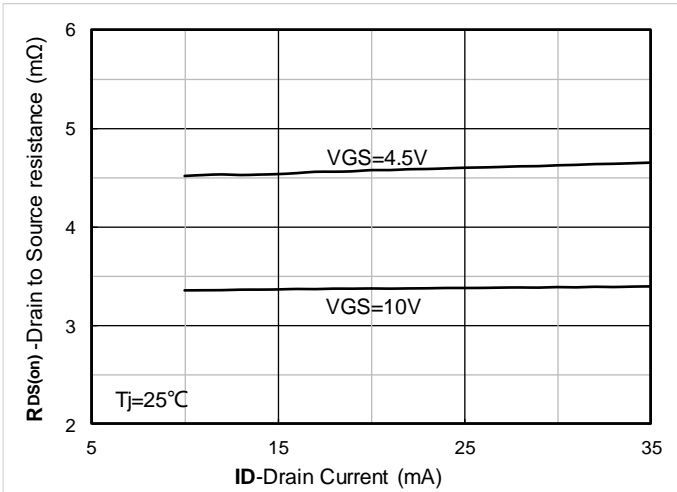


Figure 7.  $R_{DS(on)}$  VS Drain Current

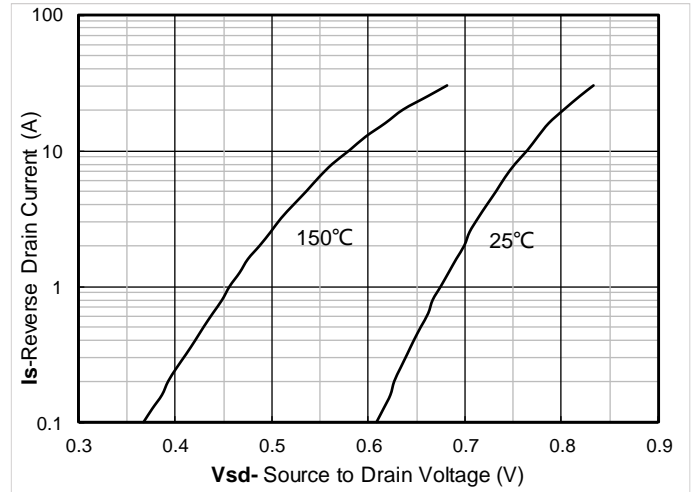


Figure 8. Forward characteristics of reverse diode

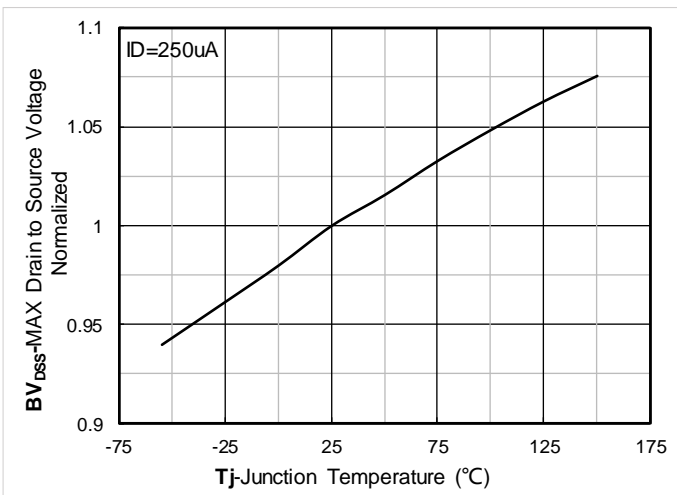


Figure 9. Normalized breakdown voltage

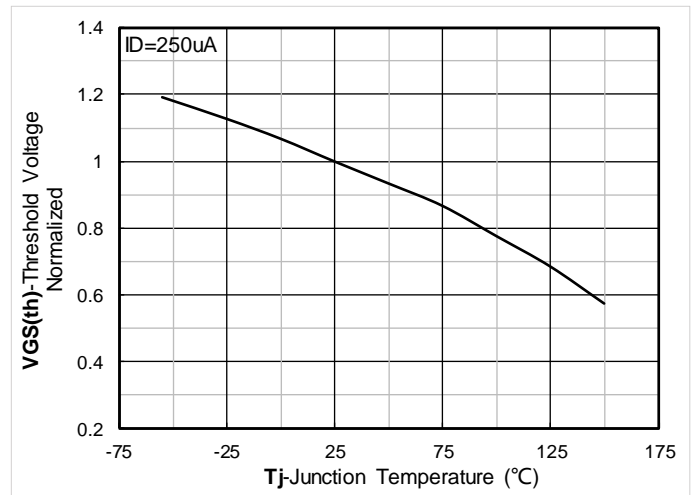


Figure 10. Normalized Threshold voltage

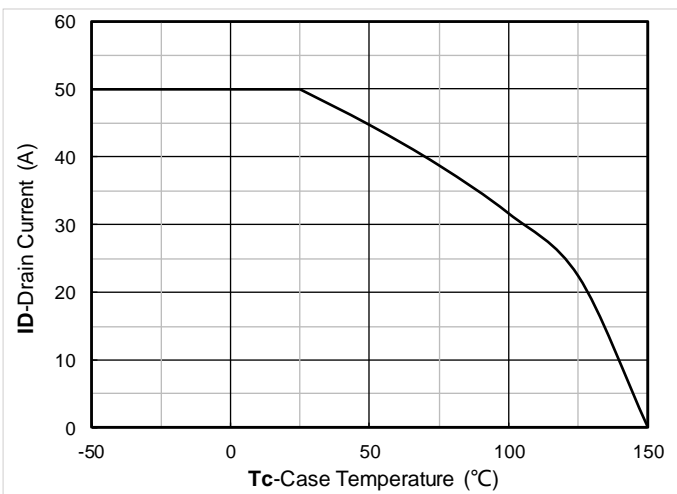


Figure 11. Current dissipation

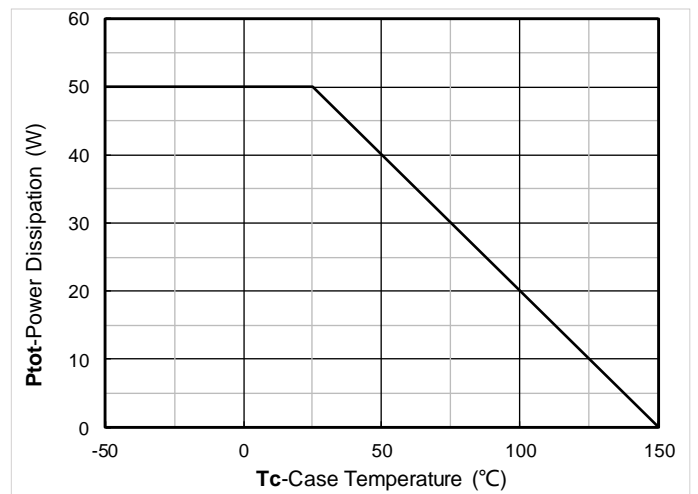


Figure 12. Power dissipation

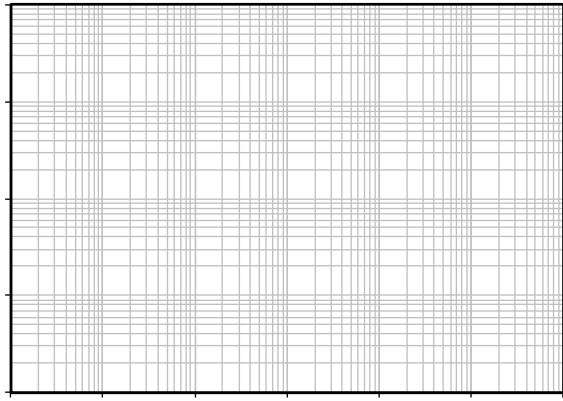


Figure 13. Maximum Transient Thermal Impedance

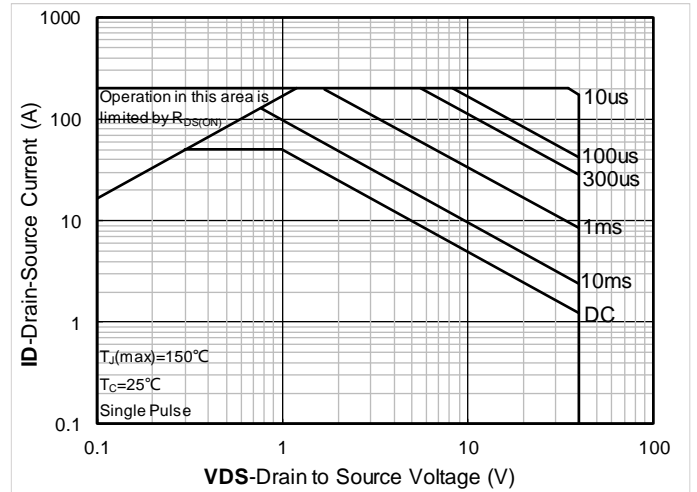


Figure 14. Safe Operation Area

## ■ Test Circuits & Waveforms

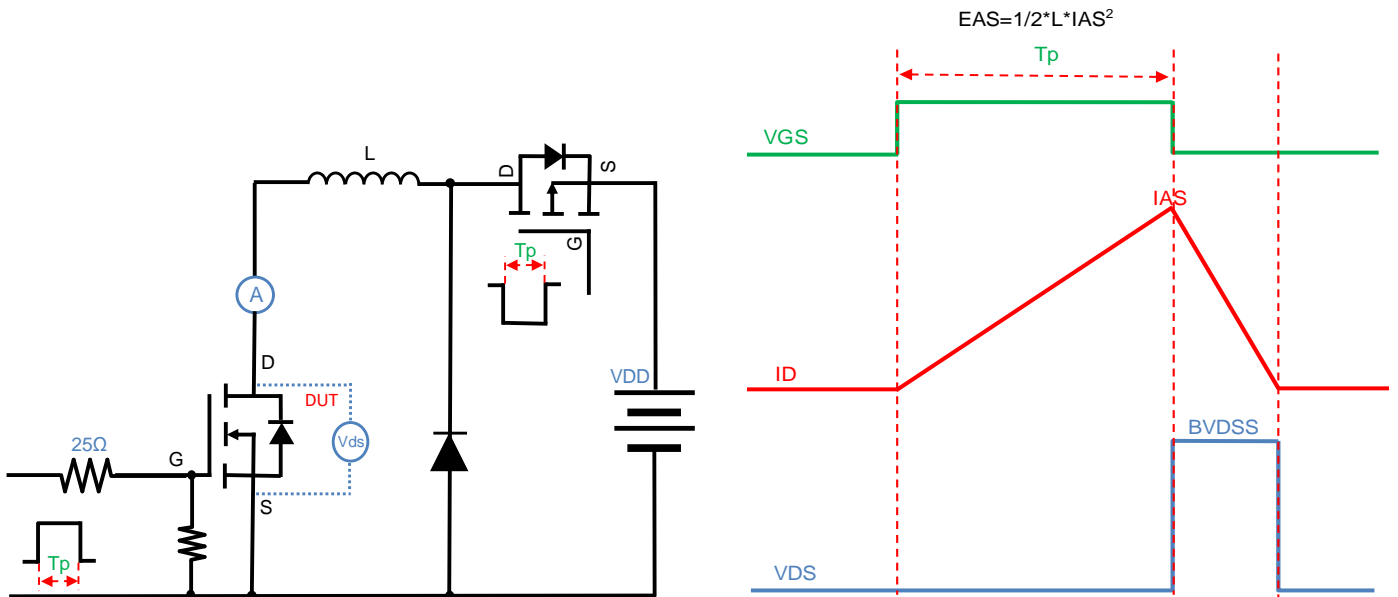


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Figure B. Gate Charge Test Circuit & Waveform

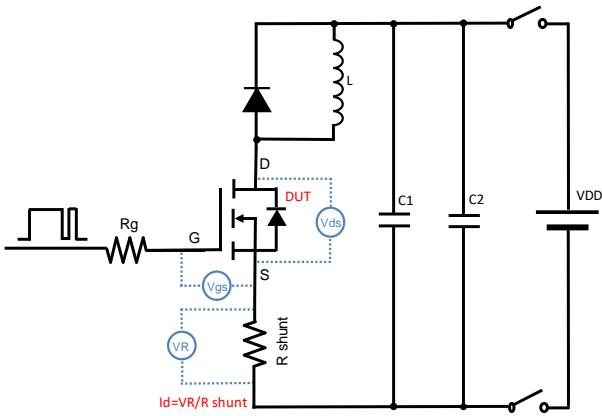


Figure C. Resistive Switching Test Circuit & Waveform

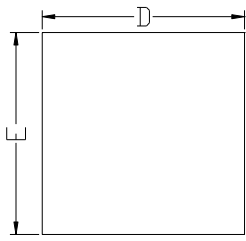


Figure D. Diode Recovery Test Circuit & Waveform

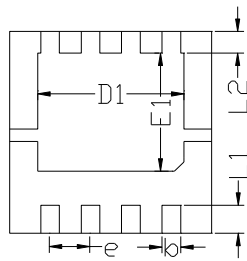


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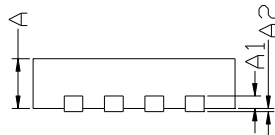
## DFN3333-8L Package information



Top View

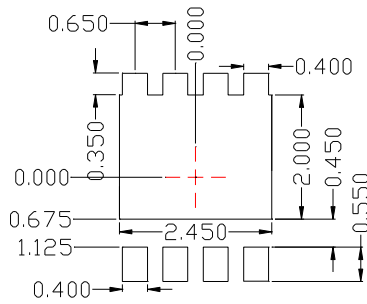


Bottom View



Side View

SYMBOL	MILLIMETER		
	MIN	NDM	MAX
D	3.15	3.25	3.35
E	3.15	3.25	3.35
A	0.70	0.80	0.90
A1	0.20 BSC		
A2			0.10
D1	2.20	2.35	2.50
E1	1.80	1.90	2.00
L1	0.35	0.45	0.55
L2	0.35 BSC		
b	0.20	0.30	0.40
e	0.65 BSC		



Suggested Solder Pad Layout  
Top View

**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.10\text{mm}$ .
3. The pad layout is for reference purposes only.



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